Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | XUE ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,608,752	08-2003	Morris et al.	361/700
	В	US-5,022,462	06-1991	Flint et al.	165/80.4
	С	US-5,651,414	07-1997	Suzuki et al.	165/104.14
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 09134653 A	05-1997	Japan	HASEGAWA et al.	H01H 37/32
1	0	JP 62046273 A	02-1987	Japan	ONO, HIDEHIKO	G01R 31/00
	Р	JP 01074799 A	03-1989	Japan	KOJIMA et al.	H05K 07/20
T	Q	JP 60030994 A	02-1985	Japan	FUJII, GENSHIRO	F28D 15/02
	R	JP 2001263971 A	09-2001	Japan	NAKAGAWA, MASAYUKI	F28D 15/02
	S	JP 07254672 A	10-1995	Japan	TAKAHASHI, HIDEKAZU	H01L 23/467
	Т	WO 9904429 A1	01-1999	World Intellect	TOPPING et al.	H01L 23/373

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYYY format are publication dates. Classifications may be US or foreign.